

Mechanical shock test method

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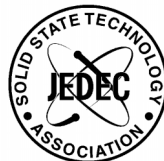
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PUBLICLY AVAILABLE SPECIFICATION



INTERNATIONAL
ELECTROTECHNICAL
COMMISSION



Reference number
IEC/PAS 62186

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JESD22-B104-A

JEDEC STANDARD

Test Method B104-A Mechanical Shock

JESD22-B104-A (Revision of Test Method B104, previously published in JEDEC Standard No. 22-B.)

SEPTEMBER 1990

ELECTRONIC INDUSTRIES ASSOCIATION
ENGINEERING DEPARTMENT



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MECHANICAL SHOCK TEST METHOD

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IEC-PAS 62186 was submitted by JEDEC and has been processed by IEC technical committee 47: Semiconductor devices.

The text of this PAS is based on the following document:

This PAS was approved for publication by the P-members of the committee concerned as indicated in the following document:

Draft PAS	Report on voting
47/1459/PAS	47/1492/RVD

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